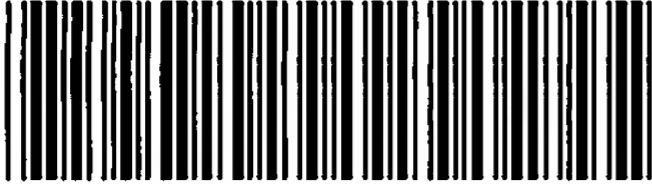


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/589,821	TANAKA ET AL.	
	Examiner	Art Unit	
	James Mackey	1722	

SEARCHED			
Class	Subclass	Date	Examiner
425	28.1, 46, 47	9/4/2007	JPM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Conducted INVENTOR name search in IFW	9/4/2007	JPM